

Abstract

A method for testing the error ratio BER of a device under
5 test against a specified allowable error ratio comprises
the steps: measuring n_s samples of the output of the
device, thereby detecting n_e erroneous samples of these n_s
samples, defining $BER(n_e) = n_e/n_s$ as the preliminary error
ratio and deciding to pass the device, if the preliminary
10 error ratio $BER(n_e)$ is smaller than an early pass limit
 $EPL(n_e)$. The early pass limit is constructed by using an
empirically or analytically derived distribution for a
specific number of devices each having the specified
allowable error ratio by separating a specific portion DD
15 of the best devices from the distribution for a specific
number of erroneous samples n_e and proceeding further with
the remaining part of the distribution for an incremented
number of erroneous samples.

20 (Fig. 7)